

Progress on development of a new TOF concept using MCP-PMT detectors at SLAC

J. Va'vra, SLAC

Light travels 300 μ m in one ps

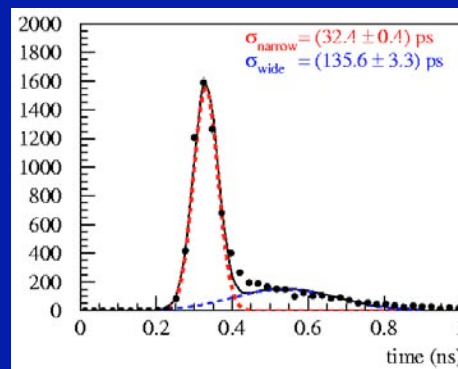
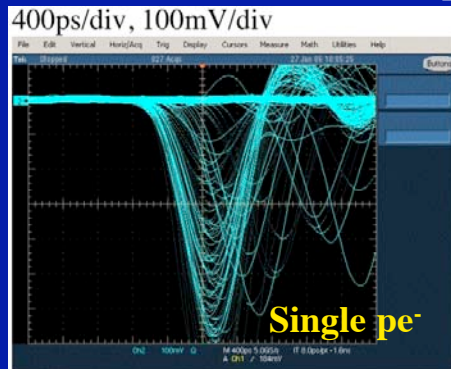
People who helped

- SLAC test beam:
J. Schwiening - DAQ system
B. Ratcliff and D. Leith - discussions
- Fermilab test beam:
E. May, C. Ertley (ANL),
E. Ramberg, A. Ronzhin (Fermilab),
T. Natoli and H. Frisch (U. of Chicago)

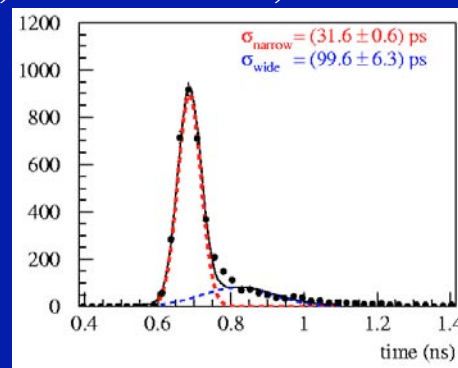
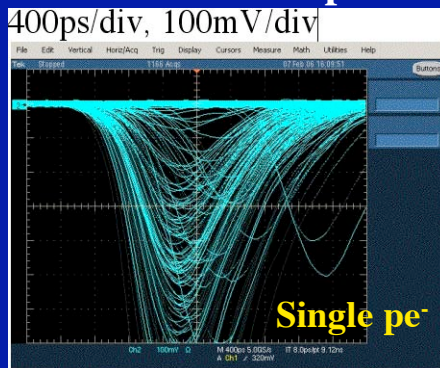
σ_{TTS} using a single Burle/Photonis MCP-PMT

J.Va'vra et al., Nucl.Instr.&Meth. A 572 (2007) 459–462

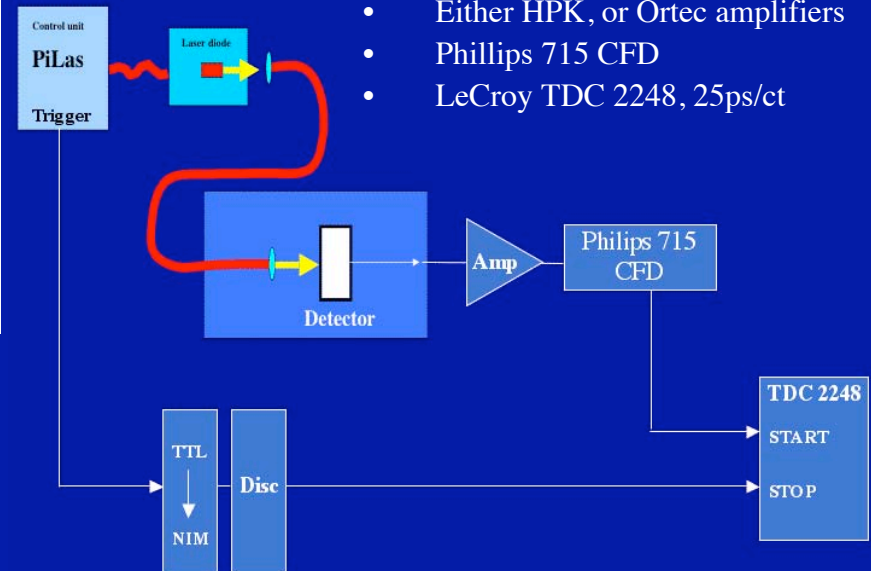
HPK C5594-44 amp., ~1.6 GHz BW, 63x:



Ortec VT-120 amp.+6dB, ~0.3 GHz BW, 100x:



- 10 μm MCP hole diameter
- 2.8kV on MCP-PMT
- Either HPK, or Ortec amplifiers
- Phillips 715 CFD
- LeCroy TDC 2248, 25ps/ct



Single pe's:

$$\sigma_{TTS} \sim \sqrt{(32^2 - 13^2 - 11^2)} = 27 \text{ ps}$$

PiLas laser diode
contribution

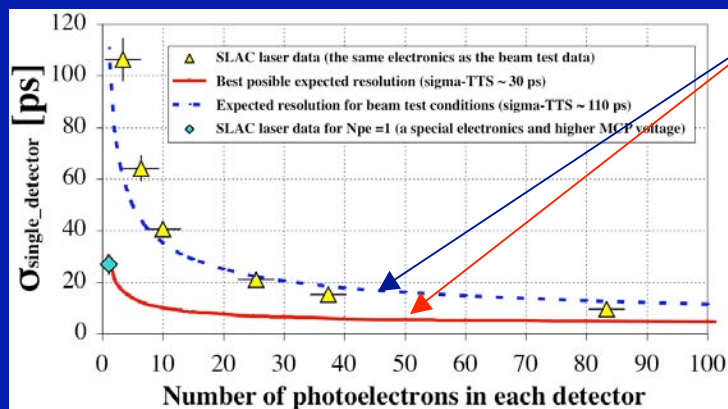
Electronics contribution
(mostly TDC)

- My best measurements of σ_{TTS} are obtained with rather slow electronic; to obtain the best result, I “tuned” a cable length between amp. & CFD (find that 20-30ns length yields the best σ_{TTS}).
- Point of this slide: one does not have to be fast to get a good σ_{TTS} !

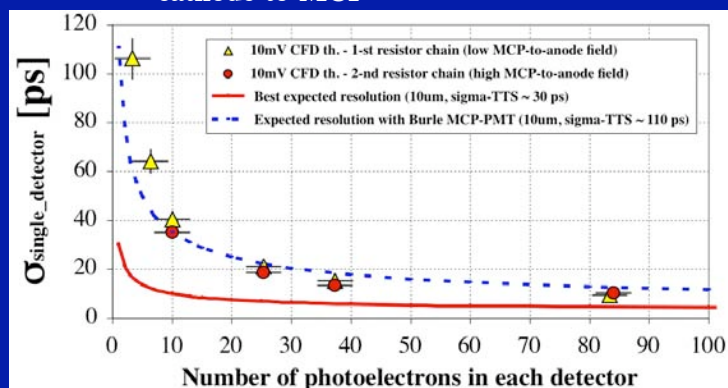
σ_{TTS} using a pair of Burle/Photonis MCP-PMTs

J.Va'vra et al., Nucl.Instr.&Meth., Trieste

Nominal MCP voltages, low gain:

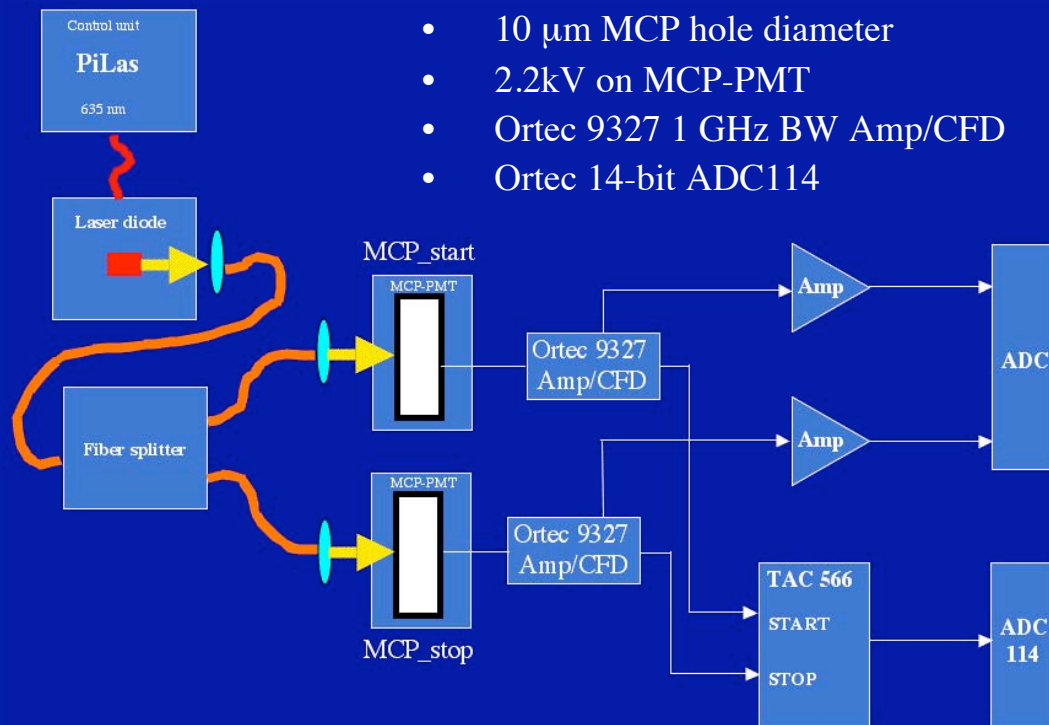


Increase $E_{\text{cathode-to-MCP}}$ field:



- Point of this slide: If one extrapolates resolution to $N_{pe} = 1$, one obtains much worse σ_{TTS} with this type of electronics !!
- Increasing $E_{\text{cathode-to-MCP}}$ field does not help much.

$$\sigma \sim \sqrt{[\sigma_{\text{MCP-PMT}}^2 + \sigma_{\text{Laser}}^2 + \sigma_{\text{Electronics}}^2 + \dots]} = \sqrt{[\sigma_{TTS}/\sqrt{N_{pe}}]^2 + \sqrt{((FWHM/2.35)/\sqrt{N_{pe}})^2 + (4.2 \text{ ps})^2}}$$

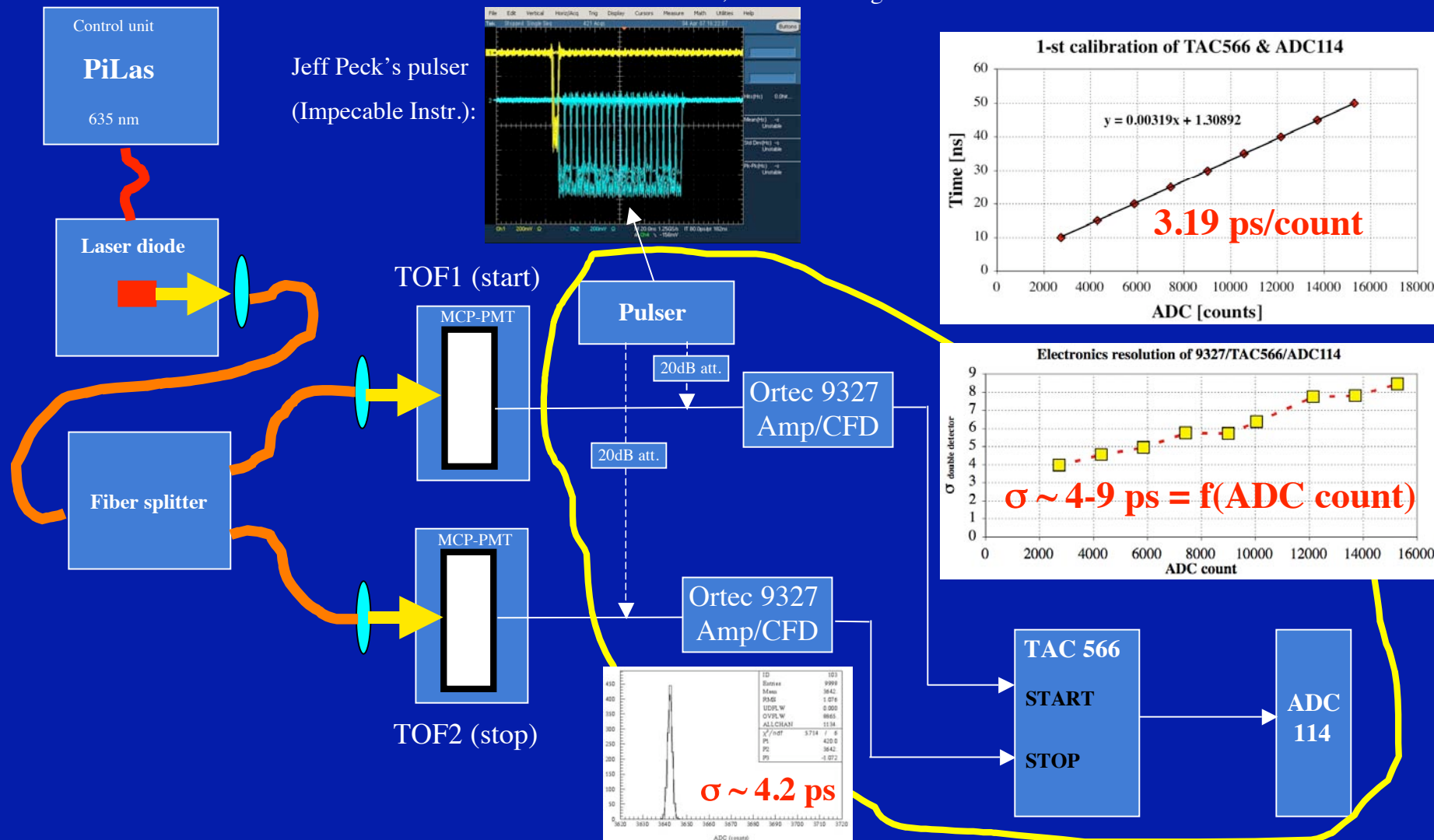


Single pe's:

σ_{TTS} (extrapolate to $N_{pe}=1$) ~ 110 ps

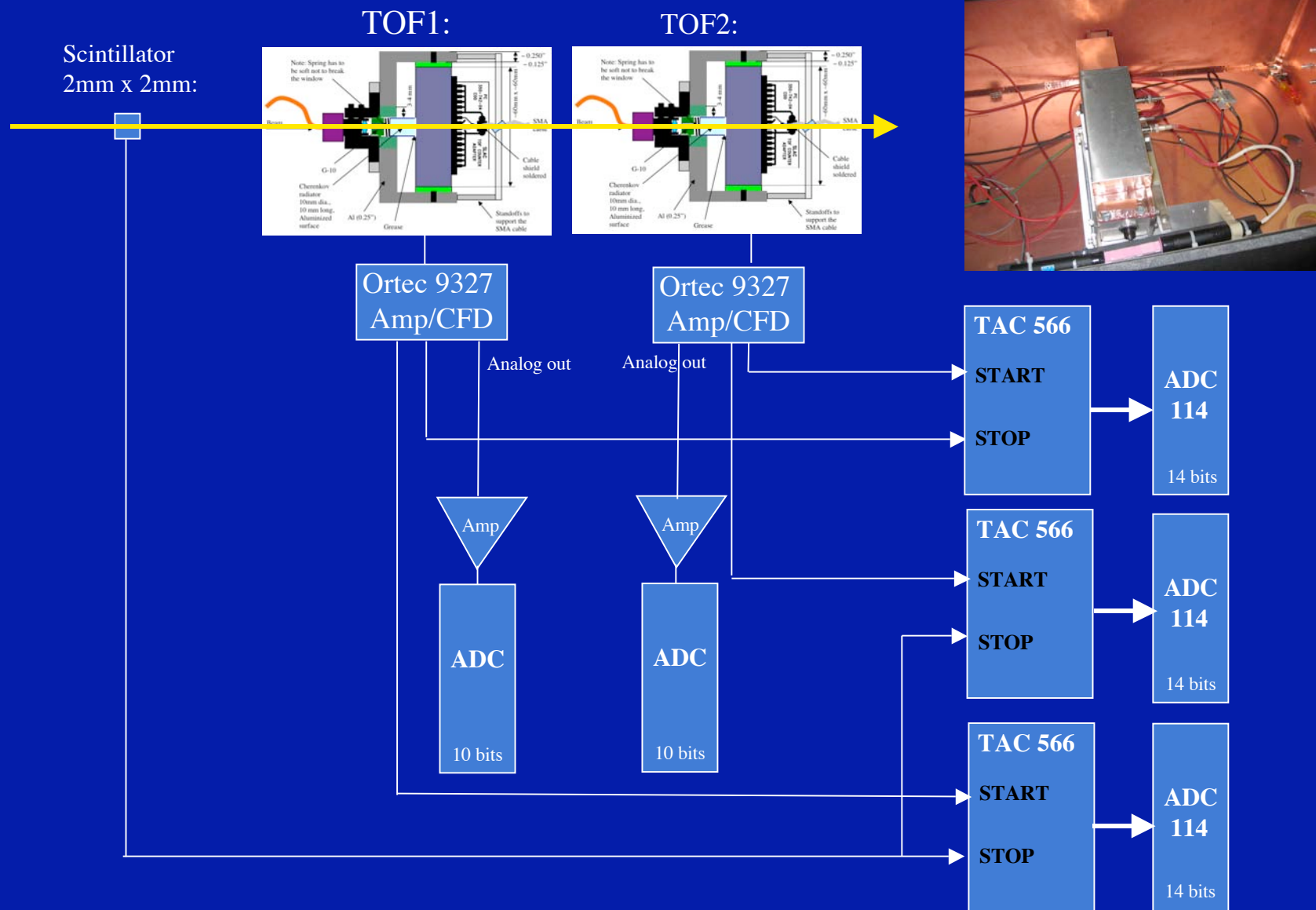
Time calibration of the electronics

J.Va'vra, MCP-PMT log book 4



- The best electronics performance, to my knowledge, but for small ADC values only.

Fermilab electronics setup with two MCP-PMTs



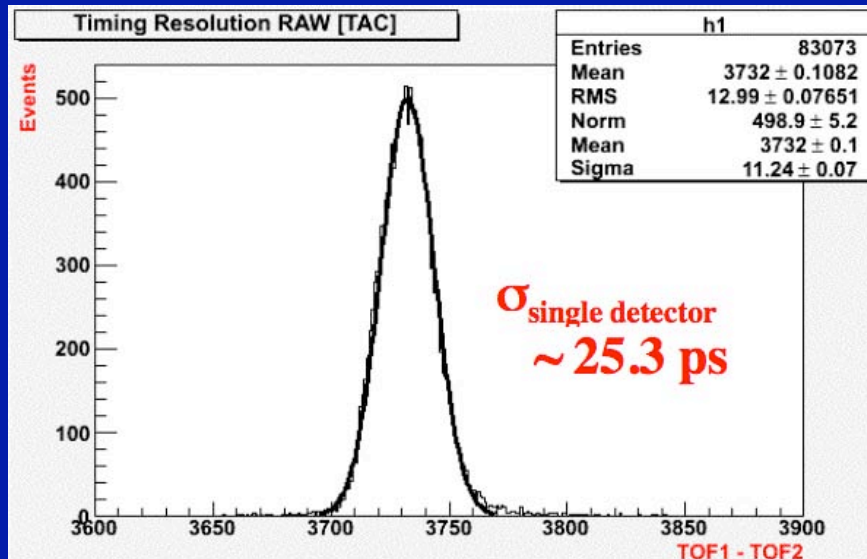
9/16/08

J. Va'vra, IEEE, Dresden, 2008

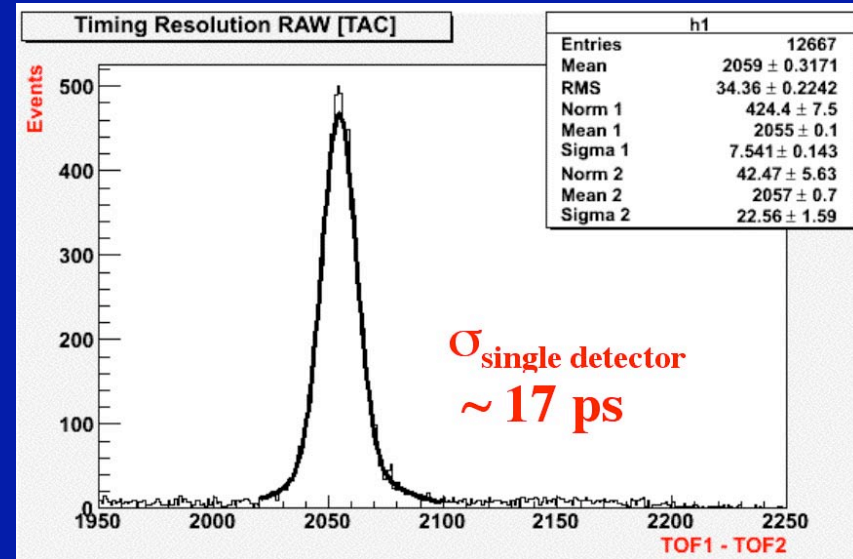
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Beam tests at SLAC and Fermilab

SLAC beam test, 10 GeV e^+ :



Fermilab beam test, 120 GeV p:

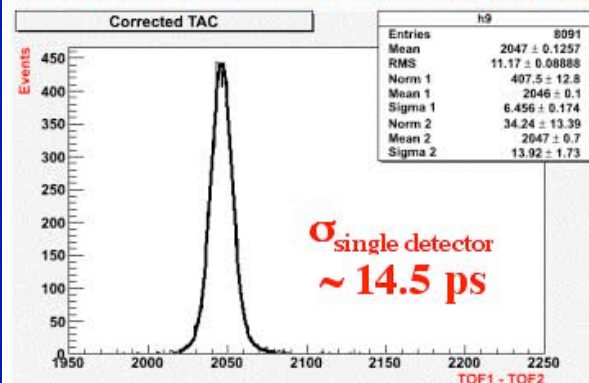


- No ADC cut or correction to CFD timing at this point
- Fermilab test: replace quartz radiator (a new aluminum coating on cylinder sides made by Photonis).

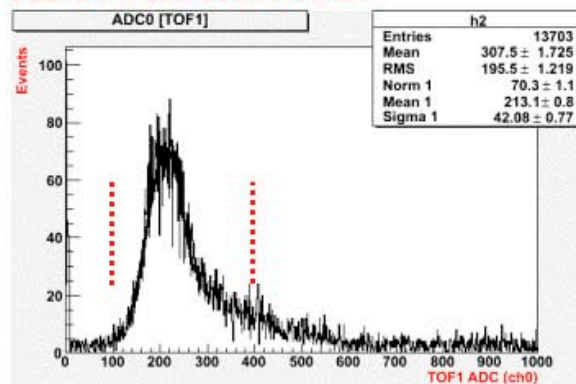
Beam test at Fermilab

120 GeV p:

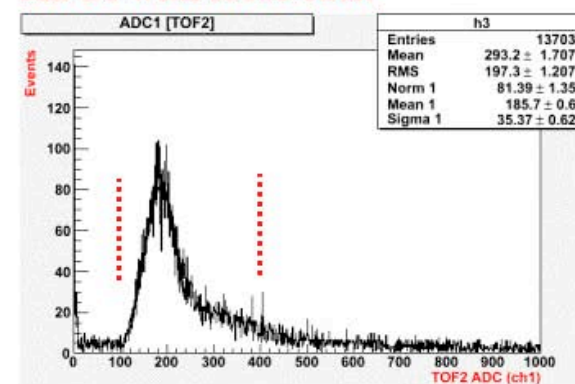
Loose ADC cuts and PH correction:



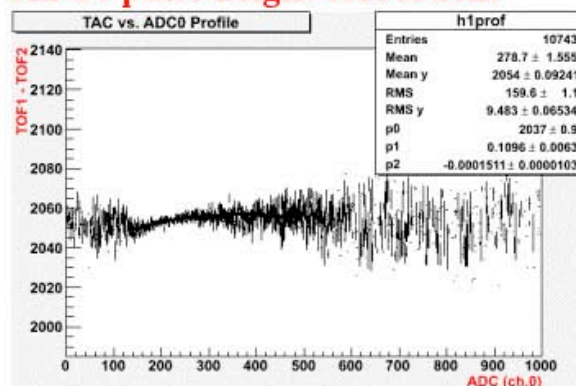
ADC0 with loose cuts:



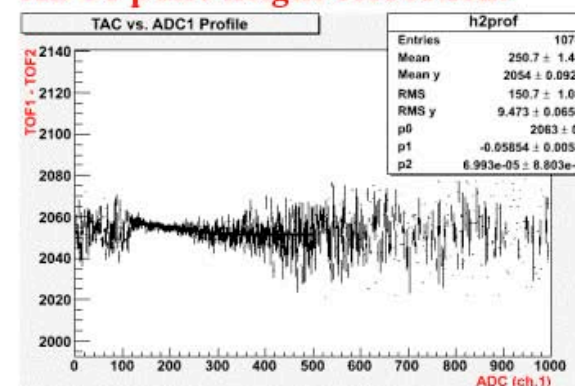
ADC1 with loose cuts:



ADC0 pulse height correction:



ADC1 pulse height correction:

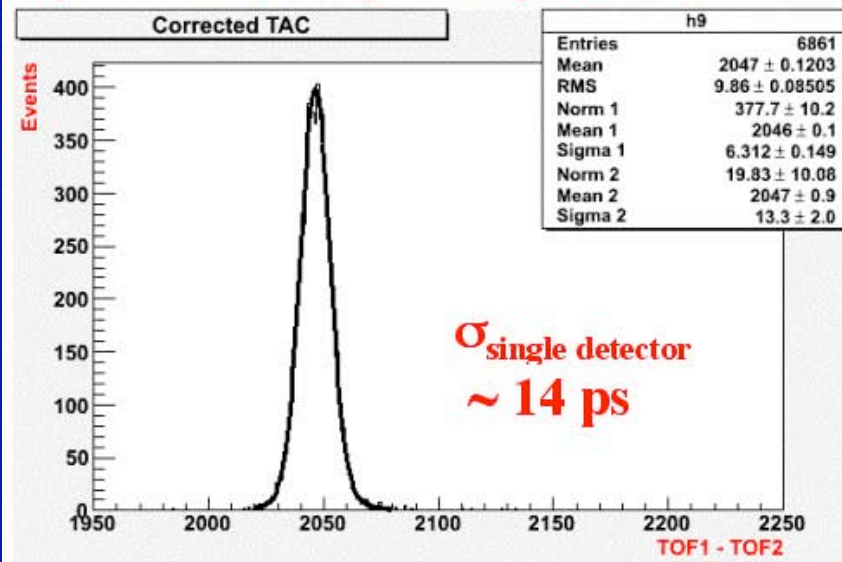


- ADC correction to CFD timing & loose ADC cuts

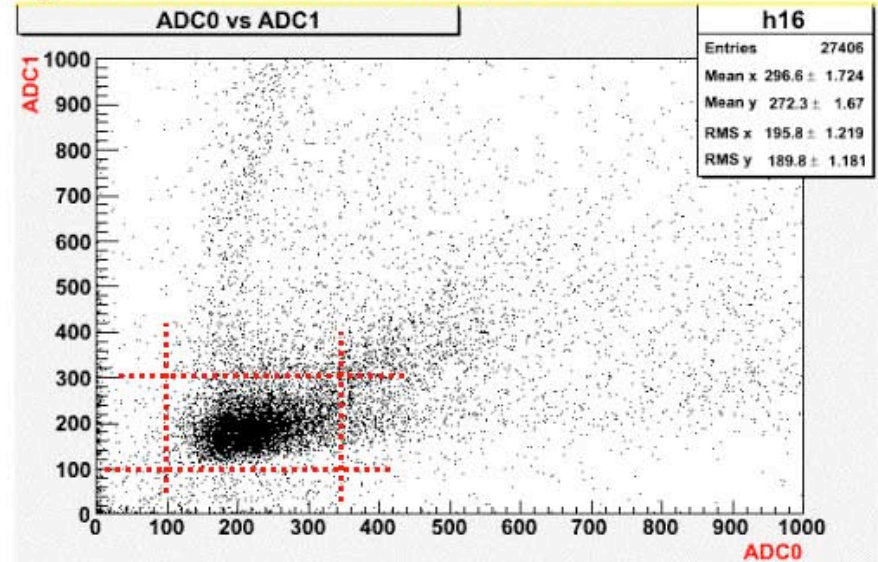
Beam test at Fermilab

120 GeV p:

Tight ADC cuts and pulse height correction:

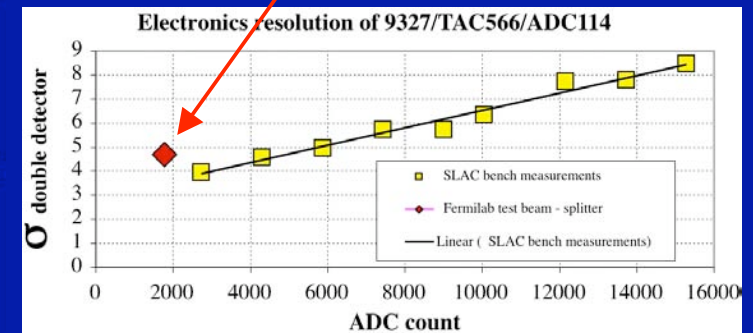
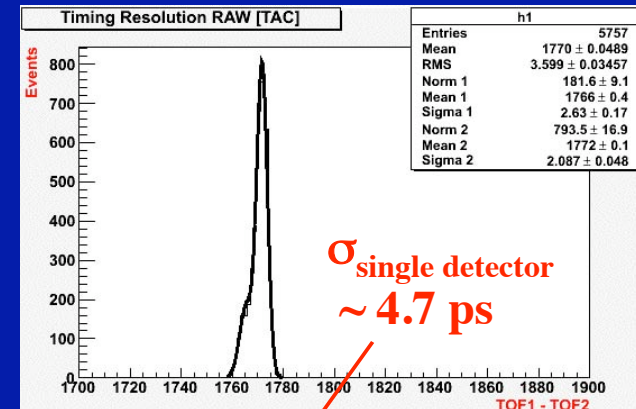
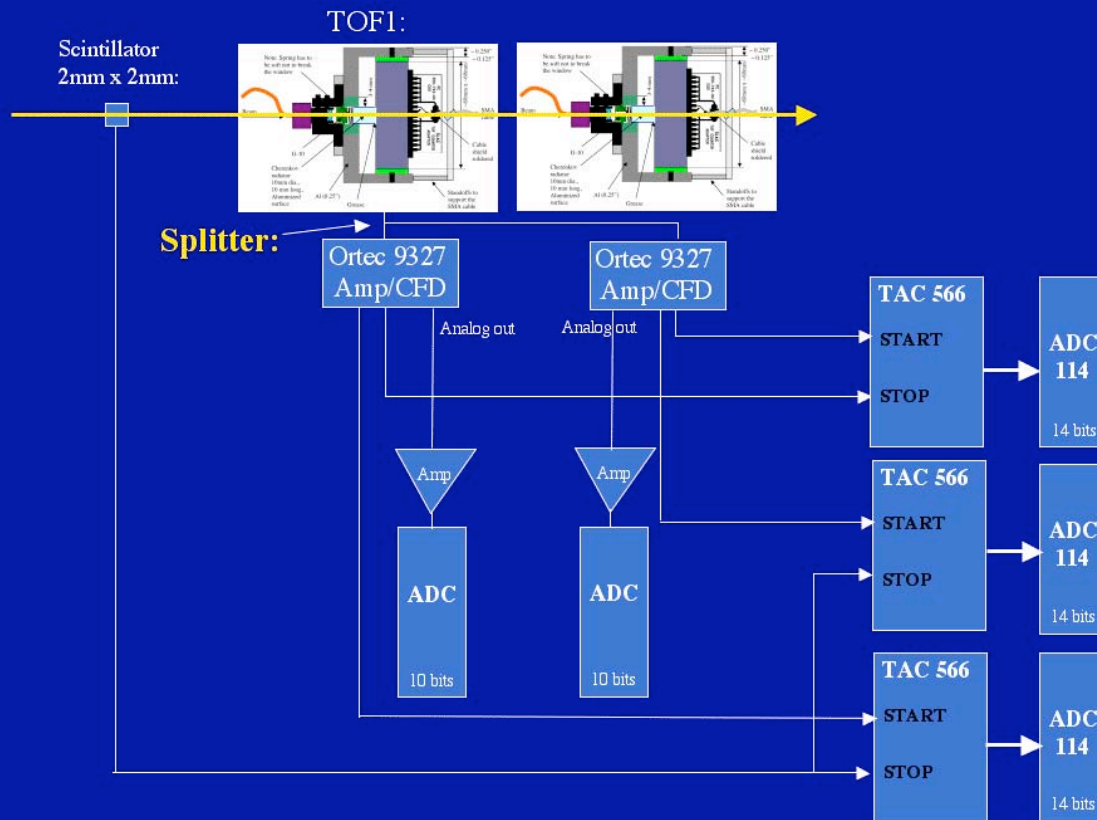


Tight ADC cuts to eliminate doubles:



- ADC correction to CFD timing & tighter ADC cuts

Fermilab: Check the electronics resolution



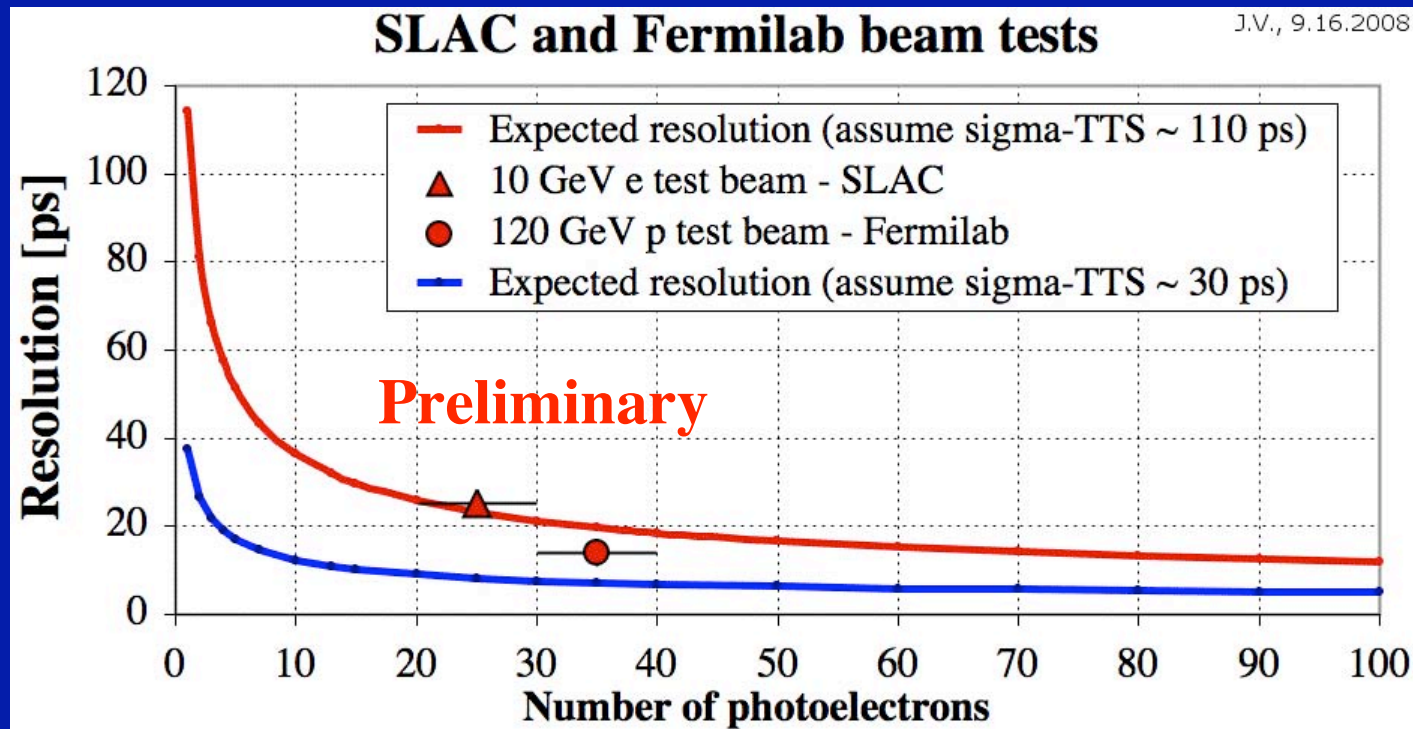
- The Fermilab beam test electronics resolution is only slightly worse than my bench measurements at SLAC.

Are the results consistent with expectations ?

$$\sigma \sim \sqrt{[\sigma_{\text{MCP-PMT}}^2 + \sigma_{\text{Radiator}}^2 + \sigma_{\text{Pad broadenibng}}^2 + \sigma_{\text{Electronics}}^2 + \dots]} =$$

$$= \sqrt{[(\sigma_{\text{TTS}}/\sqrt{N_{\text{pe}}})^2 + (((12000\mu\text{m}/\cos\Theta_C)/(300\mu\text{m/ps})/n_{\text{group}})/\sqrt{(12N_{\text{pe}})})^2 +$$

$$+ ((6000\mu\text{m}/300\mu\text{m/ps})/\sqrt{(12N_{\text{pe}})})^2 + (4.7\text{ ps})^2]}$$



- **Laser-based test:** $\sigma_{\text{TTS}} \sim 106\text{ ps}$ for $N_{\text{pe}} \sim 1$ & identical SLAC test beam electronics
- **Calculation:** $N_{\text{pe}} \sim 30$